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for copper intercon: oct grown by electrochemical displacement

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AMENDMENTS TO THE CLAIMS

The following listing of claims will replace all prior versions, and listing of claims in the application:

LISTING OF CLAIMS:

Claim : (Currently amended) At A method for forming copper interconnects including an oxygen-removing pre-process, the method comprising ine steps of:

providing a solvent;

b. heating the solvent to a boil in an open container and maintairing the boiling condition for a predetermined time period to remove dissolved exygen therefrom:

cooling the solvern

c. forming a reaction solution by mixing hydroffuoric scid and cuptic sulfate with the ocolec solven::

c. preparing a substrate with a Ti metal displacement layer;

? immersing the prepared substrate in the reaction

solution to carry out a displacement process for forming a corporation layer.

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MR1683-507 Sarial Nurther: 10/716,550 3eply: o Official Action 484cd 5 April 2004 deposition is to remove the exygen in the reaction solution before displacement and deposition—a copper film—(conducting wire such that the copper film—and has a lower electric resistance.

Claim 2 (Cancelled).

Cleim 3 (Currently amended) The exygen removing pre-process method as plaimed in claim [[2]] L. wherein the exygen in the reaction solution is removed by being bolded step of maintaining the bolding condition for a predetermined time includes the step of beiling the solvent for two minutes.

Claim 4 (Currentity amended) The oxygen-removing pre-process method as claimed in claim 3, wherein the recetion column is instincted step of cooling includes covering the container to provent the ambient oxygen in the air from being dissolved into the resetion solution solvent during cooling.

Claim 5 (Currently amended) The exygen removing pre-process method as

claimed in claim 4, wherein the step of a centainer for receiving the receiven

solution is closed to insulate the reaction solution received in the container

covering the container includes the step of covering the container with

polypropylene film to isolate the solvent from exposure to air.

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MR1683-307 Script Number: 10-716,550 Realy to Official Anion dated 5 April 3034 Claim 6 (Currently amended) The nethod as caimed in claim 1.

wherein the step of providing a solvent includes the step of providing deionized water. An axygen removing pre-greeess for electrochemical displacement deposition removing oxygen in the reaction solution by boring, the reaction solution insulated to prevent the exygen in the circler theirs dissolved into the reaction solution colution during cooling, the reaction solution mixed with liquid and provided to the electrechemical displacement deposition for reducing the electric resistance of the grown copper.

Claim 7 (Currently amended) The exygen removing pre-process mathod as claimed in claim 6, wherein the step of forming a reaction solution is mixed with deionized water includes mixing forty-millilitum of a buffered hydrofluoric acid and four-grams of cupic sulptate mixed in one liter of the deionized water.

Claims 8 - 9 (Cancelled).

Claim 10 (Currently amended) The <u>recthod</u> oxygen removing pre-pre-precess as claimed in claim 6.4, wherein the step of cooling includes the step of cooling the solvent reaction solution each for forty minutes.

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Claim 13 (Currently amended) The exygen removing one process method as claimed in claim 6 1, wherein the step of terming a Ti metal displacement layer is previously formed on the wafer by includes forming the Timetal displacement layer with a sputtering system.

Claim 14 (Currently amended). The exygen-removing pre-process method as claimed in claim 13, wherein the Timetal displacement layer formed has a thickness for of 3000 Å.

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